Notice of References Cited

Application/Control No.

10/752,428

Examiner

Christopher E. Lee

Applicant(s)/Patent Under
Reexamination
PATTERSON ET AL.

Art Unit
Page 1 of 1

U.S. PATENT DOCUMENTS

*	•	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name .	Classification
*	Α	US-6,950,893 B2	09-2005	Chan, Johni	710/240
*	В	US-2004/0083324 A1	04-2004	Rabinovitz et al.	710/315
*	C	US-2003/0050990 A1	03-2003	Craddock et al.	709/212
*	D	US-6,996,658 B2	02-2006	Brocco et al.	710/312
*	E	US-6,944,152 B1	09-2005	Heil, Tom	370/360
*	F	US-2004/0059862 A1	03-2004	Chan, Johni	710/316
*	G	US-6,882,645 B2	04-2005	Jones, lan W.	370/392
*	Н	US-2003/0126297 A1	07-2003	Olarig et al.	709/250
*	ı	US-7,010,607 B1	03-2006	Bunton, William P.	709/228
*	J	US-2003/0235042 A1	12-2003	Harris et al.	361/752
*	к	US-2004/0003154 A1	01-2004	Harris et al.	710/300
*	L	US-7,009,982 B2	03-2006	Scott et al.	370/401
*	М	US-6,667,955 B1	12-2003	Blanc et al.	370/220

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	٧						
	w						
	x						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.